

INTERNATIONAL STANDARD

NORME INTERNATIONALE

**Connectors for electronic equipment – Tests and measurements –
Part 28-100: Signal integrity tests up to 1 000 MHz on IEC 60603-7 and
IEC 61076-3 series connectors – Tests 28a to 28g**

**Connecteurs pour équipements électroniques – Essais et mesures –
Partie 28-100: Essais d'intégrité des signaux jusqu'à 1 000 MHz sur les
connecteurs des séries CEI 60603-7 et CEI 61076-3 – Essais 28a à 28g**



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INTERNATIONAL ELECTROTECHNICAL COMMISSION

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Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

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